## **74ABT00**

# Quad 2-input NAND gate Rev. 3 — 11 August 2016

**Product data sheet** 

#### 1. **General description**

The 74ABT00 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT00 is a quad 2-input NAND gate.

#### 2. Features and benefits

- Latch-up protection exceeds 500 mA per JESD78B class II level A
- ESD protection:
  - ◆ HBM JESD22-A114F exceeds 2000 V
  - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from -40 °C to +85 °C

#### **Ordering information** 3.

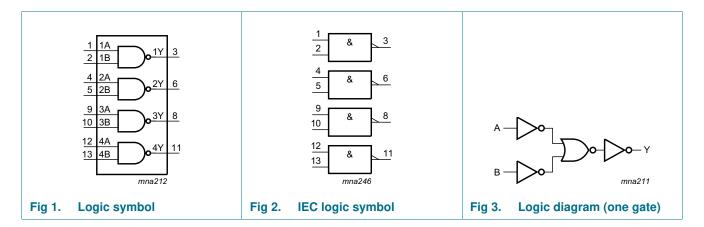
Table 1. **Ordering information** 

74ABT00DB	Package											
	Temperature range	Name	Description	Version								
74ABT00D	–40 °C to +85 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1								
74ABT00DB	–40 °C to +85 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1								
74ABT00PW	–40 °C to +85 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1								



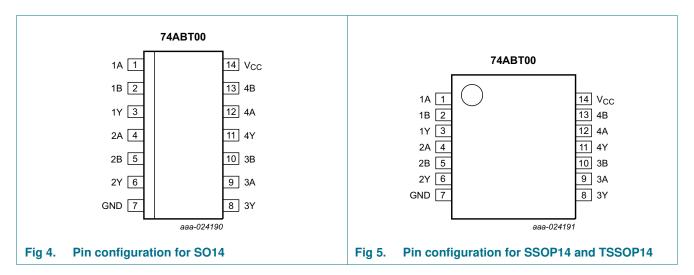
**Quad 2-input NAND gate** 

## 4. Functional diagram



## 5. Pinning information

#### 5.1 Pinning



#### 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
1A to 4A	1, 4, 9, 12	data input
1B to 4B	2, 5, 10, 13	data input
1Y to 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V <sub>CC</sub>	14	supply voltage

**Quad 2-input NAND gate** 

## 6. Functional description

Table 3. Function table[1]

Input		Output
nA	nB	nY
L	X	Н
X	L	Н
Н	Н	L

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care.

## 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+7.0	V
V <sub>I</sub>	input voltage	[1]	-1.2	+7.0	V
Vo	output voltage	output HIGH or LOW	-0.5	+5.5	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-18	-	mA
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	-	mA
Io	output current	output in LOW-state	-	40	mA
Tj	junction temperature	[2]	-	150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## 8. Recommended operating conditions

Table 5. Operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CC</sub>	supply voltage		4.5	-	5.5	V
V <sub>I</sub>	input voltage		0	-	V <sub>CC</sub>	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.8	V
I <sub>OH</sub>	HIGH-level output current		-15	-	-	mA
I <sub>OL</sub>	LOW-level output current		-	-	20	mA
Δt/ΔV	input transition rise and fall rate		0	-	5	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	-	+85	°C

<sup>[2]</sup> The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

**Quad 2-input NAND gate** 

## 9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions			25 °C		–40 °C t	o +85 °C	Unit
	$\begin{array}{c} \text{input clamping voltage} & V_{CC} = 4.5 \text{ V; } I_{IK} = -18 \text{ mA} \\ \\ \text{HIGH-level output} & V_{CC} = 4.5 \text{ V; } I_{OH} = -15 \text{ mA;} \\ \\ \text{voltage} & V_I = V_{IL} \text{ or } V_{IH} \\ \\ \text{LOW-level output} & V_{CC} = 4.5 \text{ V; } I_{OL} = 20 \text{ mA;} \\ \\ \text{voltage} & V_I = V_{IL} \text{ or } V_{IH} \\ \\ \text{input leakage current} & V_{CC} = 5.5 \text{ V; } V_I = \text{GND or } 5.5 \text{ V} \\ \\ \text{power-off leakage} & V_{CC} = 0 \text{ V; } V_I \text{ or } V_O \leq 4.5 \text{ V} \\ \\ \text{current} & \text{output high leakage} \\ \\ \text{current} & V_{CC} = 5.5 \text{ V; } V_I = \text{GND or } V_{CC} \\ \\ \text{output current} & V_{CC} = 5.5 \text{ V; } V_O = 2.5 \text{ V} \\ \\ \end{array}$			Min	Тур	Max	Min	Max	
V <sub>IK</sub>	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$		-1.2	-0.9	-	-1.2	-	V
V <sub>OH</sub>	· ·	0		2.5	2.9	-	2.5	-	V
V <sub>OL</sub>	•	· · · · · · · · · · · · · · · ·		-	0.35	0.5	-	0.5	V
I <sub>I</sub>	input leakage current	V <sub>CC</sub> = 5.5 V; V <sub>I</sub> = GND or 5.5 V		-	±0.01	±1.0	-	±1.0	μΑ
I <sub>OFF</sub>	'	$V_{CC} = 0 \text{ V}; V_I \text{ or } V_O \le 4.5 \text{ V}$		-	±5.0	±100	-	±100	μΑ
I <sub>CEX</sub>		, 6		-	5.0	50	-	50	μА
Io	output current	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	[1]	-50	-75	-180	-50	-180	mA
I <sub>CC</sub>	supply current	$V_{CC} = 5.5 \text{ V}; V_I = \text{GND or } V_{CC}$		-	2	50	-	50	μΑ
$\Delta I_{CC}$	additional supply current	per input pin; V <sub>CC</sub> = 5.5 V; one input at 3.4 V; other inputs at V <sub>CC</sub> or GND	[2]	-	0.25	500	-	500	μΑ
Cı	input capacitance	V <sub>I</sub> = 0 V or V <sub>CC</sub>		-	3	-	-	-	рF

<sup>[1]</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

## 10. Dynamic characteristics

**Table 7. Dynamic characteristics** GND = 0 V; for test circuit, see <u>Figure 7</u>.

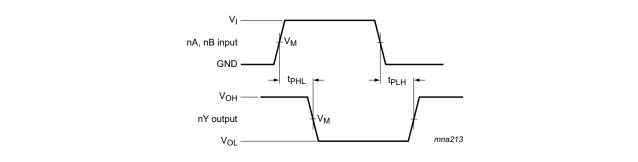
Symbol	Parameter	Conditions	25 °C	25 °C; V <sub>CC</sub> = 5.0 V			-40 °C to +85 °C; V <sub>CC</sub> = 5.0 V ± 0.5 V				
			Min	Тур	Max	Min	Max				
t <sub>PLH</sub>	LOW to HIGH propagation delay	nA, nB to nY; see Figure 6	1.0	2.5	3.6	1.0	4.1	ns			
t <sub>PHL</sub>	HIGH to LOW propagation delay	nA, nB to nY; see Figure 6	1.0	2.0	2.8	1.0	3.4	ns			
t <sub>sk(o)</sub>	output skew time	[1]	-	0.4	0.5	-	0.5	ns			

<sup>[1]</sup> Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.

<sup>[2]</sup> This is the increase in supply current for each input at 3.4 V.

**Quad 2-input NAND gate** 

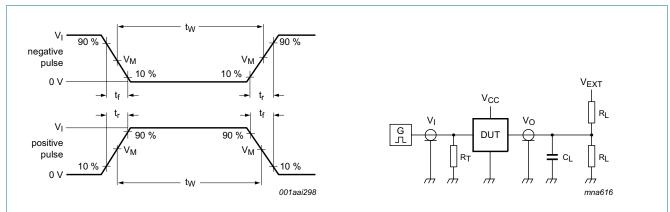
#### 11. Waveforms



 $V_{M} = 1.5 V$ 

 $\ensuremath{V_{OL}}$  and  $\ensuremath{V_{OH}}$  are typical output voltage levels that occur with the output load.

Fig 6. Propagation delay input (nA, nB) to output (nY) and output skew time



a. Input pulse definition

b. Test circuit

Test data is given in Table 8.

 $R_L$  = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_{T}$  = Termination resistance should be equal to output impedance  $Z_{o}$  of the pulse generator.

 $V_{\text{EXT}}$  = External voltage for measuring switching times.

Fig 7. Test circuit for measuring switching times

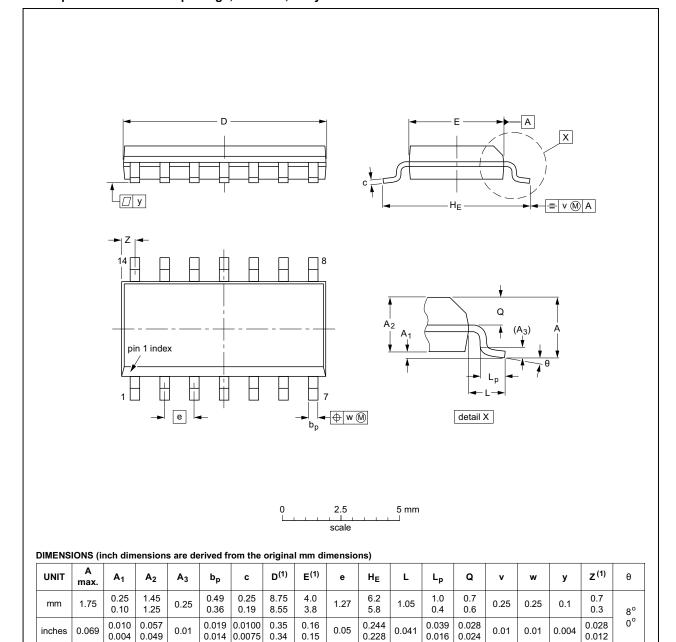
Table 8. Test data

Input			Load	V <sub>EXT</sub>		
$V_{I}$	f <sub>i</sub>	t <sub>W</sub>	t <sub>r</sub> , t <sub>f</sub>	CL	R <sub>L</sub>	t <sub>PHL</sub> , t <sub>PLH</sub>
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	open

## 12. Package outline

#### SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

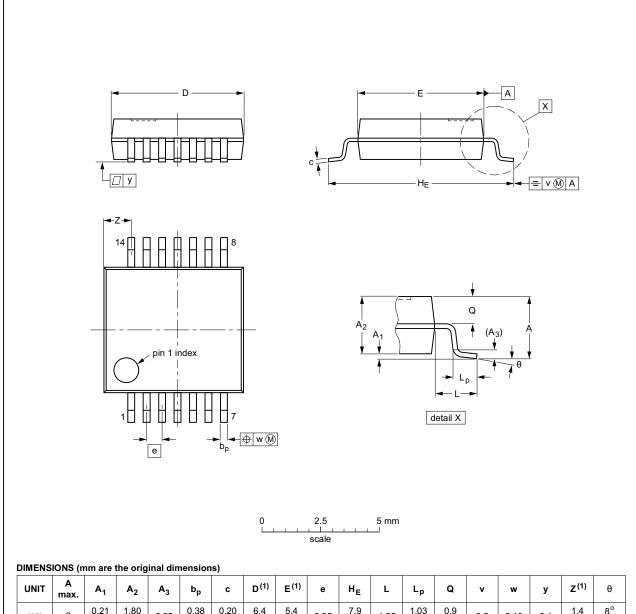
OUTLINE	MEDION					ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	1330E DATE		
SOT108-1	076E06	MS-012				<del>99-12-27</del> 03-02-19		
						03		

Fig 8. Package outline SOT108-1 (SO14)

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SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	<b>A</b> <sub>3</sub>	b <sub>p</sub>	C	D <sup>(1)</sup>	E <sup>(1)</sup>	e	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.4 0.9	8° 0°

#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT337-1		MO-150			<del>99-12-27</del> 03-02-19
	L	L			

Package outline SOT337-1 (SSOP14) Fig 9.

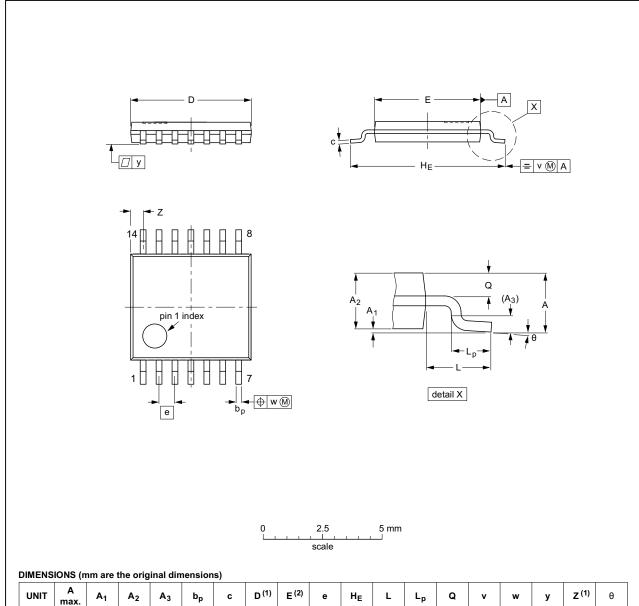
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TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	<b>A</b> <sub>3</sub>	bp	С	D <sup>(1)</sup>	E (2)	е	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

ISSUE DATE	EUROPEAN	REFERENCES			OUTLINE		
ISSUE DATE	PROJECTION		JEITA	JEDEC	IEC	VERSION	
<del>99-12-27</del> 03-02-18				MO-153		SOT402-1	
				MO-153		SOT402-1	

Fig 10. Package outline SOT402-1 (TSSOP14)

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## 13. Abbreviations

#### Table 9. Abbreviations

Acronym	Description
BiCMOS	Bipolar Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model

## 14. Revision history

#### Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ABT00 v.3	20160811	Product data sheet	-	74ABT00 v.2
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>			
<ul> <li>Legal texts have been adapted to the new company name where the company name with the company nam</li></ul>				e appropriate.
74ABT00 v.2	19950918	Product specification	-	-

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